

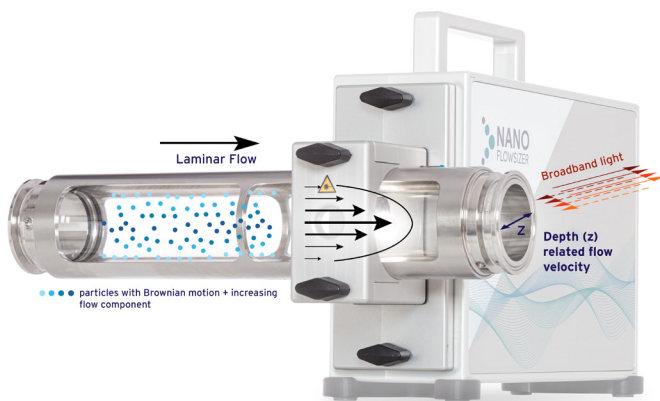
SR-DLS

THE TECHNOLOGY

- Is based on low-coherence interferometry providing instantaneous scattering information as a function of depth in the sample
- Automatically deals with multiple scattering from the depth-resolved data which allows measurements at any turbidity
- Corrects for flow contribution resulting in real-time particle size distribution data of flowing nanosuspensions

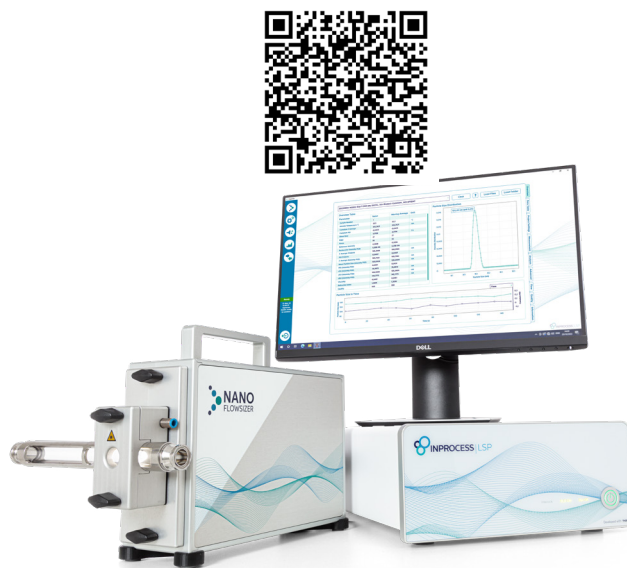
THE ADVANTAGES

- Flexibility for measurements in most types of transparent containers
- Particle size characterization in process flows ranging from static to >200L/hr
- The backscatter geometry and optics enable easy integration as a non-invasive process monitoring PAT tool



Particle motion in the flowcell module

INNOVATION, EXCELLENCE AND SYNERGY



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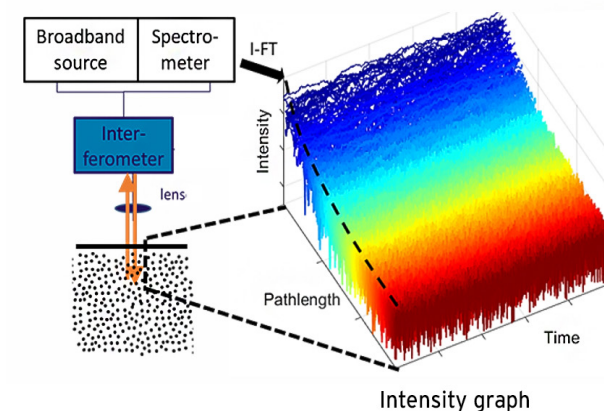
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Spatially Resolved Dynamic Light Scattering (SR-DLS)

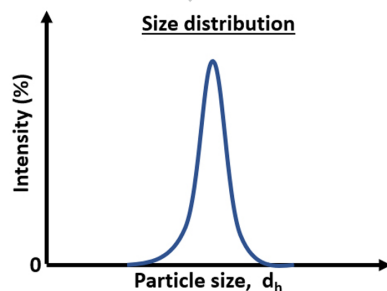
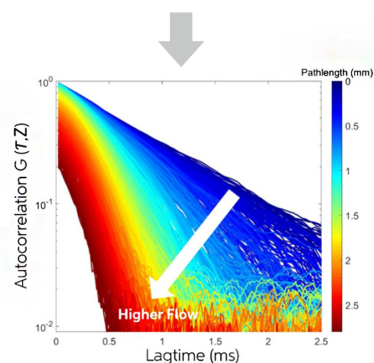
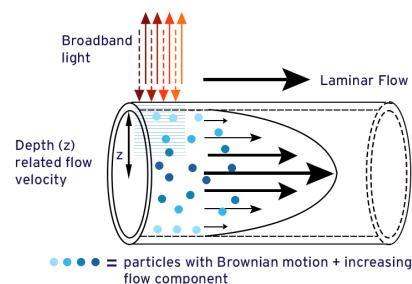
- ✓ Novel technique for real-time, continuous measurement of nanoparticles in flow and static
- ✓ Patented technology, owned by InProcess-LSP (WO2019125155A1)



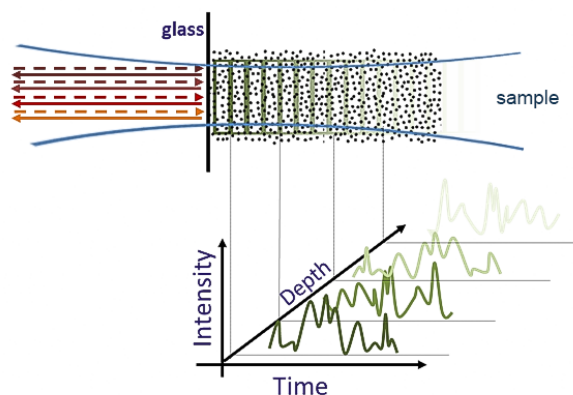
Nanoparticle characterization by SR-DLS

SR-DLS technology explained

Unique features offered by SR-DLS



The flow corrected auto-correlation functions can be processed into reliable particle size information.



SR-DLS:

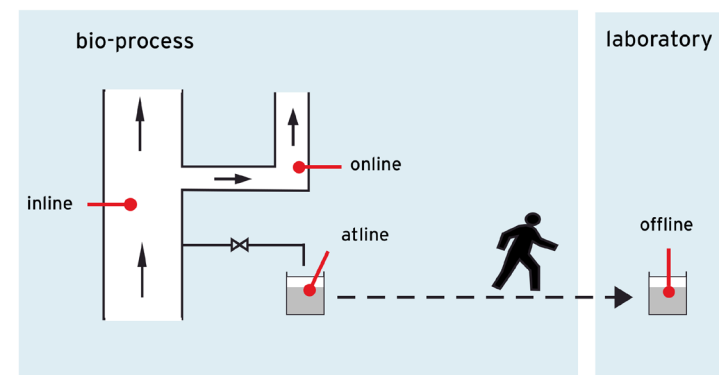
- ✓ Multiple (1000+) intensity timetraces
- ✓ Depth resolved scattering information (~ 3mm)
- ✓ Output: PDI, D90, Z-average



DLS range

SR-DLS range

SR-DLS allows nanoparticle analysis in highly turbid suspensions



Nanoparticle analysis in different configurations